

**Search Notes**

Application/Control No.

10/825,806

Examiner

David T. Fidei

Applicant(s)/Patent under  
Reexamination

TAKAHASHI ET AL.

Art Unit

3728

**SEARCHED**

Class	Subclass	Date	Examiner
206	219 220 222		
215	Dig.8	10/2/2005	DTF

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR